

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Iiro HIETANEN et al. Conf.

Application No. **NEW NATIONAL PHASE** Group

Filed May 3, 2005 Examiner

SYNCHRONOUS OPTICAL MEASUREMENT AND INSPECTION METHOD AND MEANS

**PRELIMINARY AMENDMENT**

Assistant Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

May 3, 2005

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begin on page 3 of this paper.

**Remarks** begin on page 10 of this paper.

An **Appendix** is attached following the signature page of this paper.